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|-----------------------------------|---------------------------------------|--|--|-------------|
| Notice of References Cited | Application/Control No. 10/583,480 | | Applicant(s)/Patent Under Reexamination LIETZ ET AL. | |
| | Examiner EDWARD J. KIM | | Art Unit 2455 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-4,737,953 A | 04-1988 | Koch et al. | 370/401 |
| * | B | US-4,922,503 A | 05-1990 | Leone, Mario J. | 370/402 |
| * | C | US-4,933,938 A | 06-1990 | Sheehy, David B. | 370/401 |
| * | D | US-2003/0021280 A1 | 01-2003 | Makinson et al. | 370/401 |
| * | E | US-6,519,671 B1 | 02-2003 | Kondou et al. | 710/311 |
| * | F | US-6,587,875 B1 | 07-2003 | Ogus, Aaron W. | 709/223 |
| * | G | US-2007/0274330 A1 | 11-2007 | Lietz et al. | 370/402 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(e).)
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